IXYS

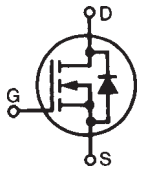
PolarHV™ HiPerFET Power MOSFET

IXFR 36N60P

V_{DSS} = 600 V
I_{D25} = 20 A
$R_{DS(on)}$ ≤ 200 mΩ
t_{rr} ≤ 200 ns

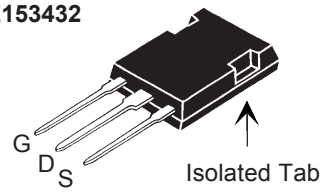
(Electrically Isolated Back Surface)

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode



Symbol	Test Conditions	Maximum Ratings	
V_{DSS}	T_J = 25°C to 150°C	600	V
V_{DGR}	T_J = 25°C to 150°C; R_{GS} = 1 MΩ	600	V
V_{GSS}	Continuous	±30	V
V_{GSM}	Transient	±40	V
I_{D25}	T_C = 25°C	20	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	80	A
I_{AR}	T_C = 25°C	36	A
E_{AR}	T_C = 25°C	50	mJ
E_{AS}	T_C = 25°C	1.5	J
dv/dt	$I_S \le I_{DM}$, di/dt ≤100 A/μs, $V_{DD} \le V_{DSS}$, $T_J \le 150°C$, R_G = 2 Ω	20	V/ns
P_D	T_C = 25°C	208	°C
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C
T_{SOLD}	Plastic body for 10 s	260	°C
V_{ISOL}	50/60 Hz, RMS, 1 minute	2500	V~
F_C	Mounting force	20..120/4.6..27	N/lb
Weight		5	g

ISOPLUS247 (IXFR)
E153432



G = Gate D = Drain
S = Source

Features

- Silicon chip on Direct-Copper-Bond substrate
  - High power dissipation
  - Isolated mounting surface
  - 2500V electrical isolation
- International standard package
- Fast recovery diode
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
  - easy to drive and to protect

Symbol	Test Conditions (T_J = 25°C, unless otherwise specified)	Characteristic Values Min.	Typ.	Max.	
BV_{DSS}	V_{GS} = 0 V, I_D = 250 μA	600			V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 4 mA	3.0		5.0	V
I_{GSS}	V_{GS} = ±30 V, V_{DS} = 0 V			±100	nA
I_{DSS}	$V_{DS} = V_{DSS}$			25	μA
	V_{GS} = 0 V, T_J = 125°C			250	μA
$R_{DS(on)}$	V_{GS} = 10 V, $I_D = I_T$ (note 1) Pulse test, t ≤300 μs, duty cycle d ≤ 2 %			200	mΩ

Advantages

- Easy to mount
- Space savings
- High power density

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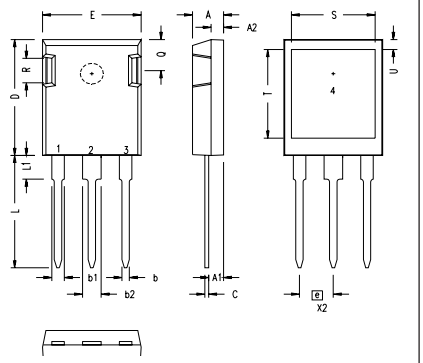
Symbol	Test Conditions	Characteristic Values (T_J = 25° C, unless otherwise specified) Min.	Typ.	Max.	
g_{fs}	V_{DS} = 20 V; I_D = I_T, pulse test	25	40		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		5800		pF
C_{oss}			570		pF
C_{rss}			30		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = I_T R_G = 2 Ω (External)		30		ns
t_r			25		ns
$t_{d(off)}$			80		ns
t_f			22		ns
$Q_{g(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = I_T		102		nC
Q_{gs}			34		nC
Q_{gd}			36		nC
R_{thJC}				0.6	°C/W
R_{thCS}			0.15		°C/W

Note 1: Test current I_T = 18 A

Source-Drain Diode

Symbol	Test Conditions	Characteristic Values (T_J = 25° C, unless otherwise specified) Min.	Typ.	Max.	
I_S	V_{GS} = 0 V			36	A
I_{SM}	Repetitive			80	A
V_{SD}	I_F = I_S, V_{GS} = 0 V, Pulse test, t ≤300 µs, duty cycle d≤ 2 %			1.5	V
t_{rr}	I_F = 25A, -di/dt = 100 A/µs			200	ns
Q_{RM}	V_R = 100V, V_{GS} = 0 V		0.8		µC
I_{RM}			6.0		A

ISOPLUS247 (IXFR) Outline



SYM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

1 – GATE
2 – DRAIN (COLLECTOR)
3 – SOURCE (EMITTER)
4 – NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or moreof the following U.S. patents: 4,835,592 4,850,072 4,881,106 4,931,844 5,017,508 5,034,796 5,049,961 5,063,307 5,187,117 5,237,481 5,381,025 5,486,715 6,162,665 6,259,123 B1 6,306,728 B1 6,404,065 B1 6,534,343 6,583,505 6,683,344 6,710,405B2 6,710,463 6,727,585 6,759,692 6,771,478 B2

Fig. 1. Output Characteristics @ 25°C

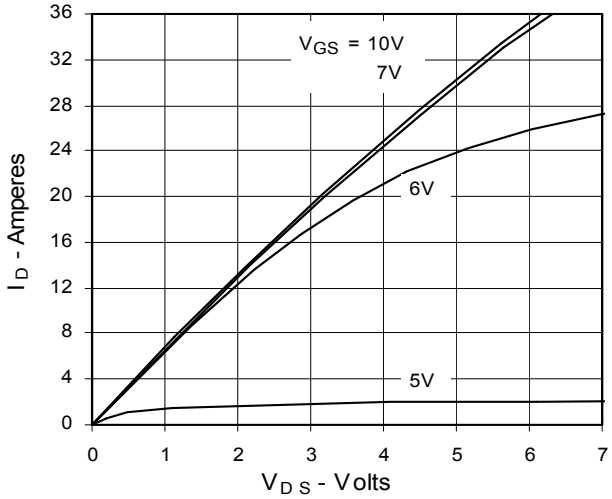


Fig. 2. Extended Output Characteristics @ 25°C

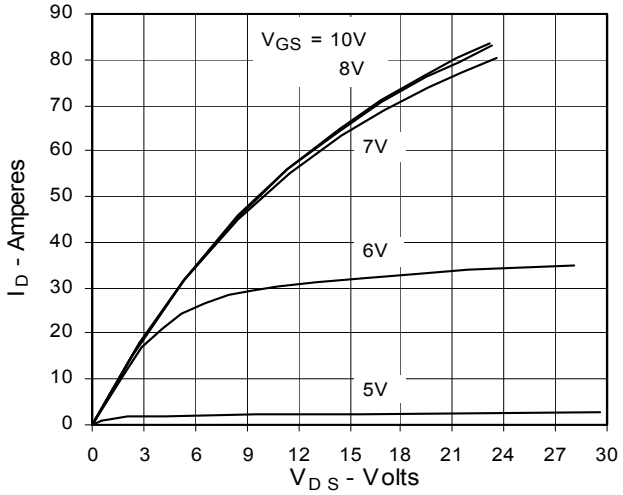


Fig. 3. Output Characteristics @ 125°C

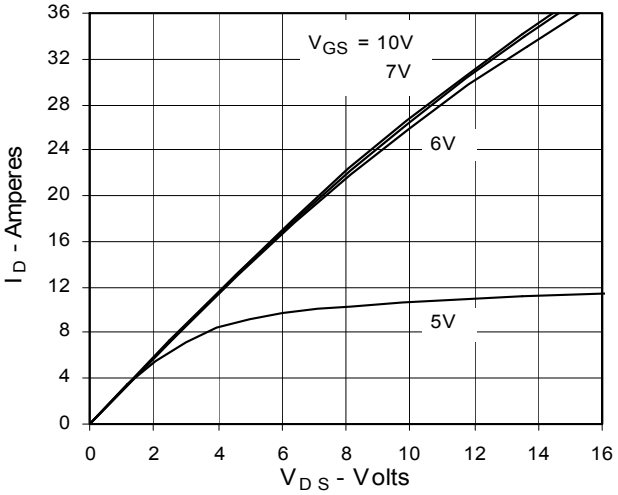


Fig. 4. $R_{DS(on)}$ Normalized to I_D = 18A Value vs. Junction Temperature

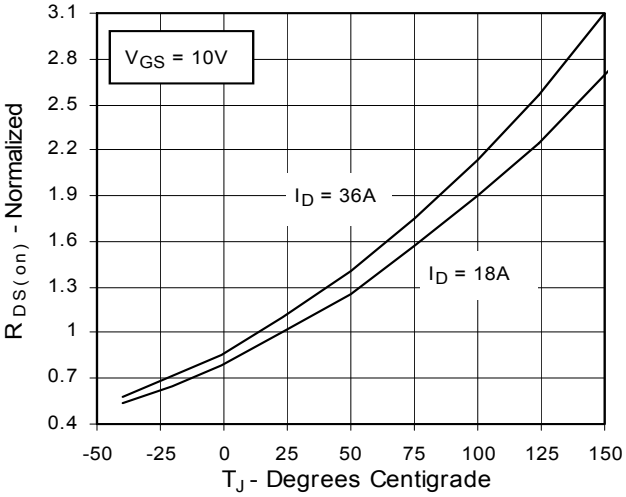


Fig. 5. $R_{DS(on)}$ Normalized to I_D = 18A Value vs. I_D

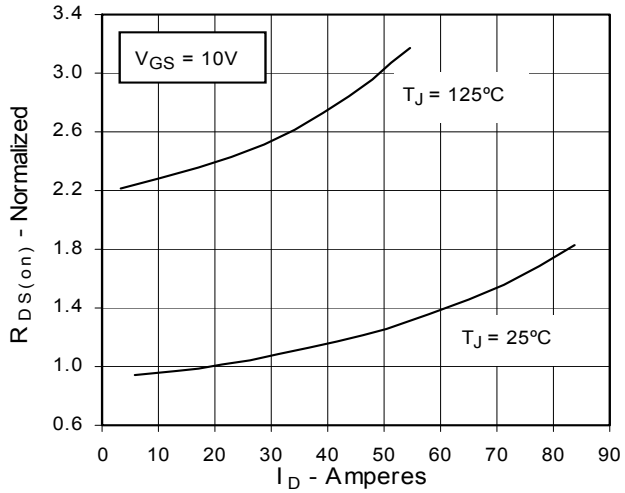
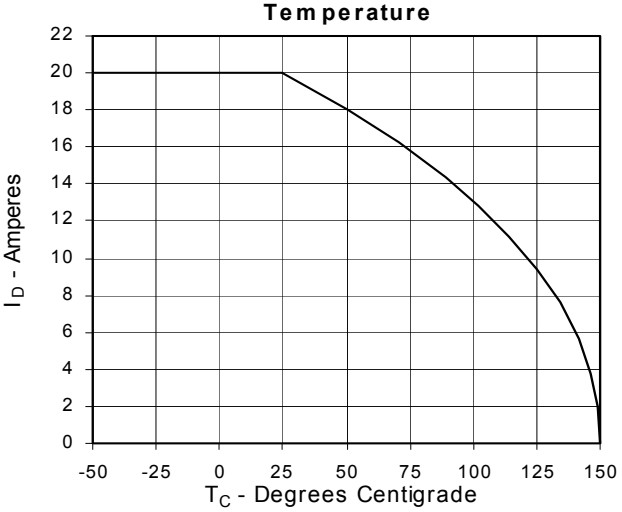


Fig. 6. Drain Current vs. Case Temperature



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Fig. 7. Input Admittance

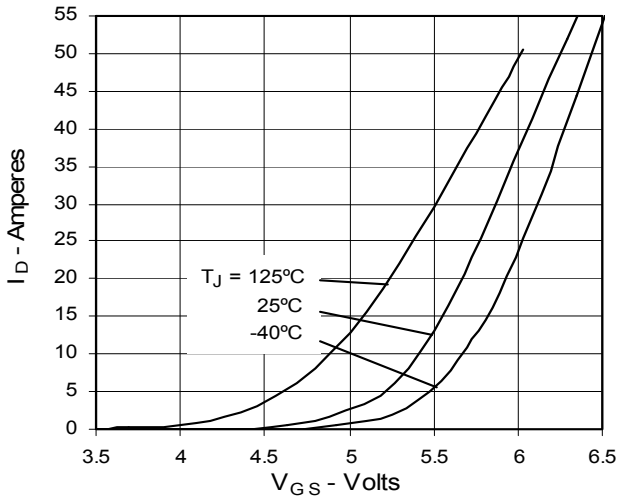


Fig. 8. Transconductance

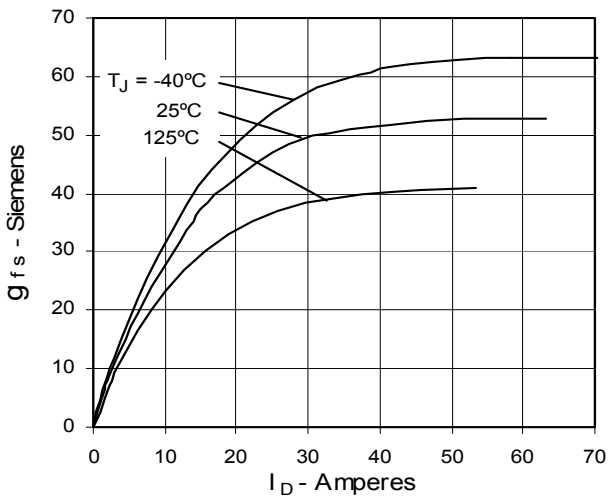


Fig. 9. Source Current vs. Source-To-Drain Voltage

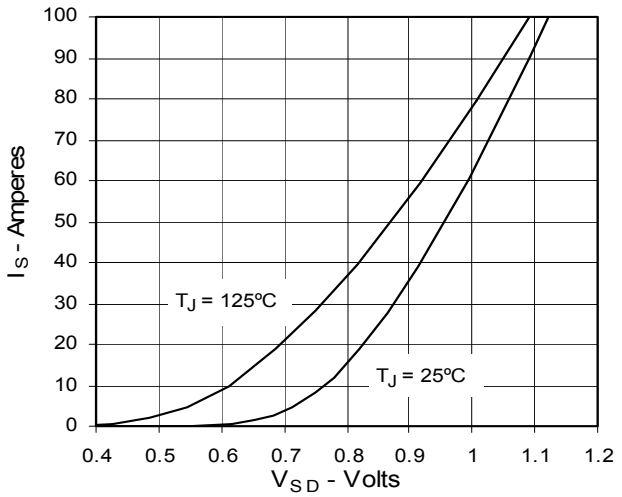


Fig. 10. Gate Charge

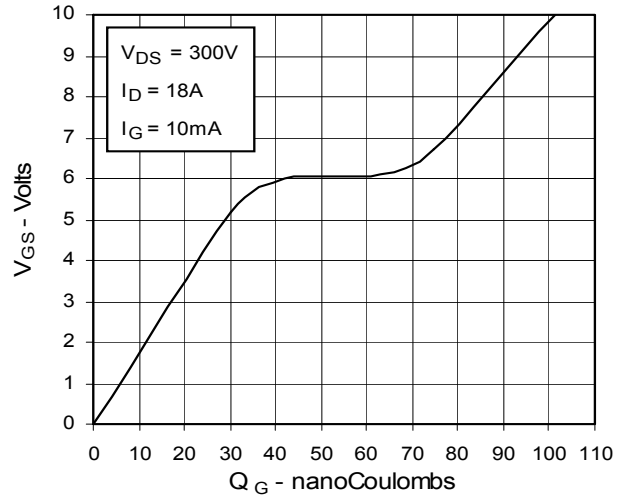


Fig. 11. Capacitance

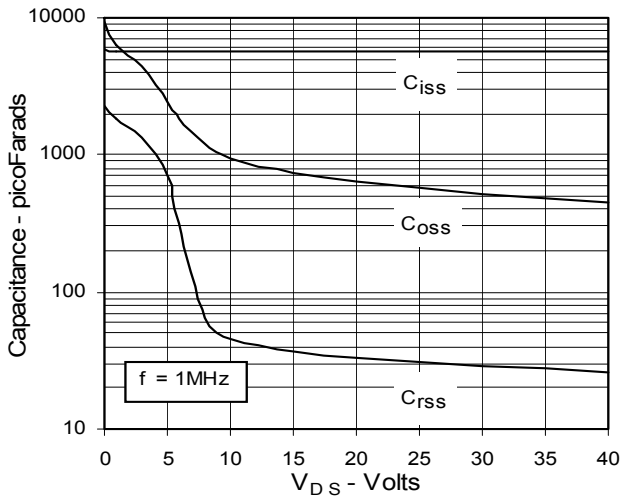
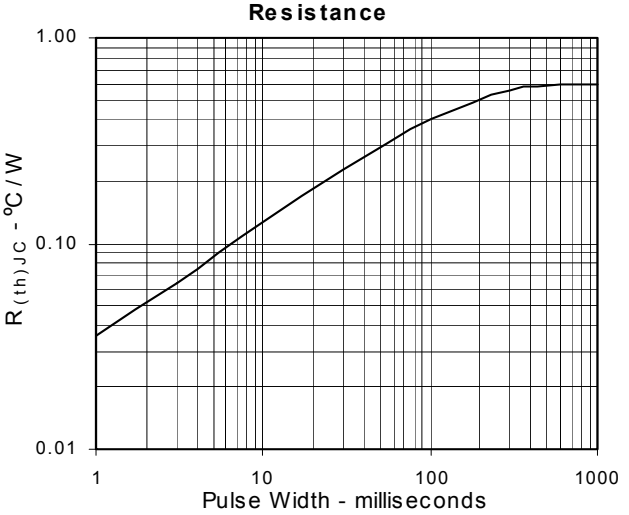


Fig. 12. Maximum Transient Thermal Resistance



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